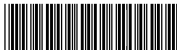


Search Notes**Application/Control No.**

10/849,724

Examiner

HUYEN X. VO

**Applicant(s)/Patent under
Reexamination**

TAKIGUCHI ET AL.

Art Unit

2626

SEARCHED

Class	Subclass	Date	Examiner
704	231; 243; 244; 250; 210; 226	6/3/2008	HV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update EAST search included IEEE search	6/3/2008	HV